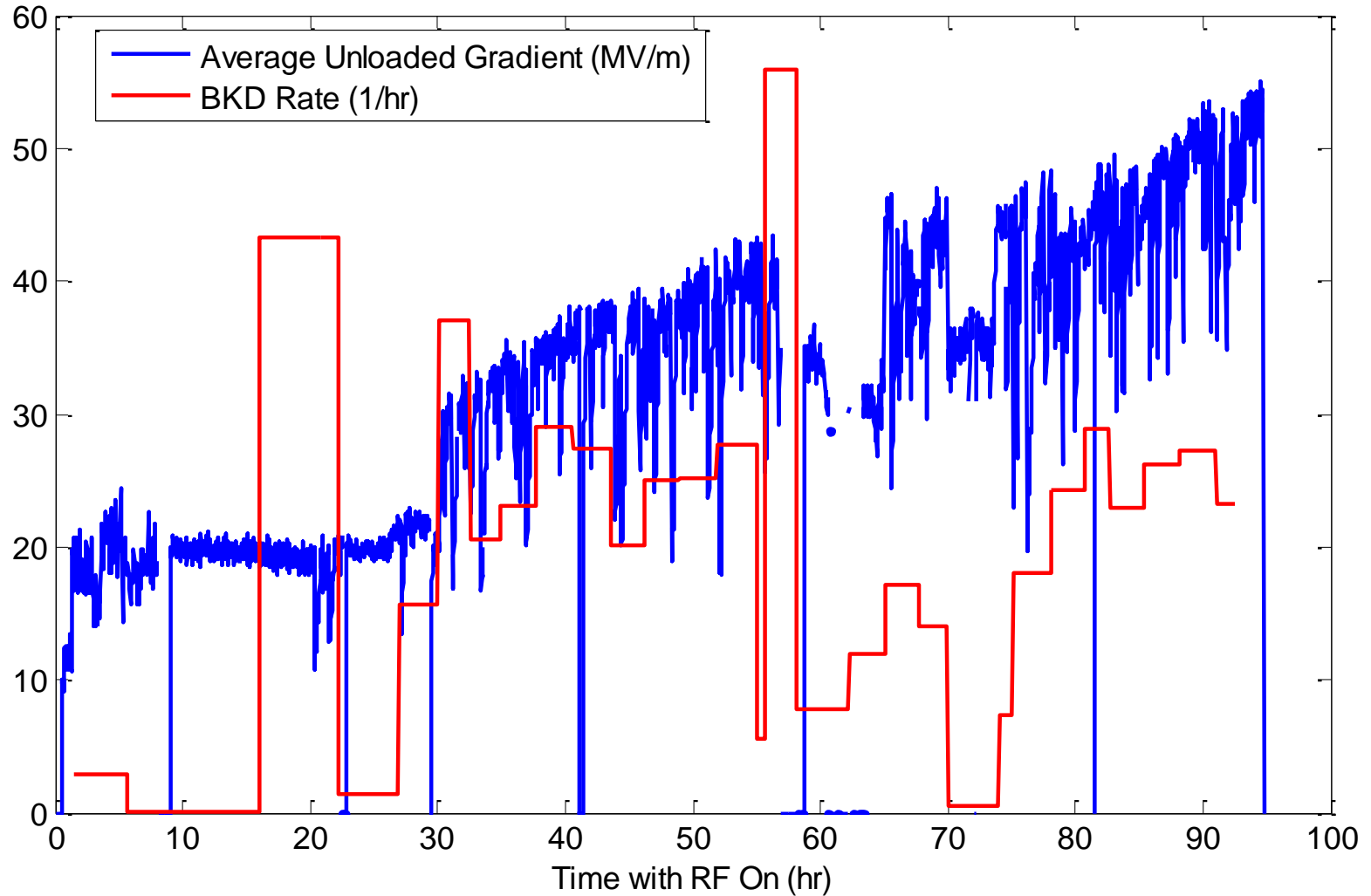


T24 High Power Test Result

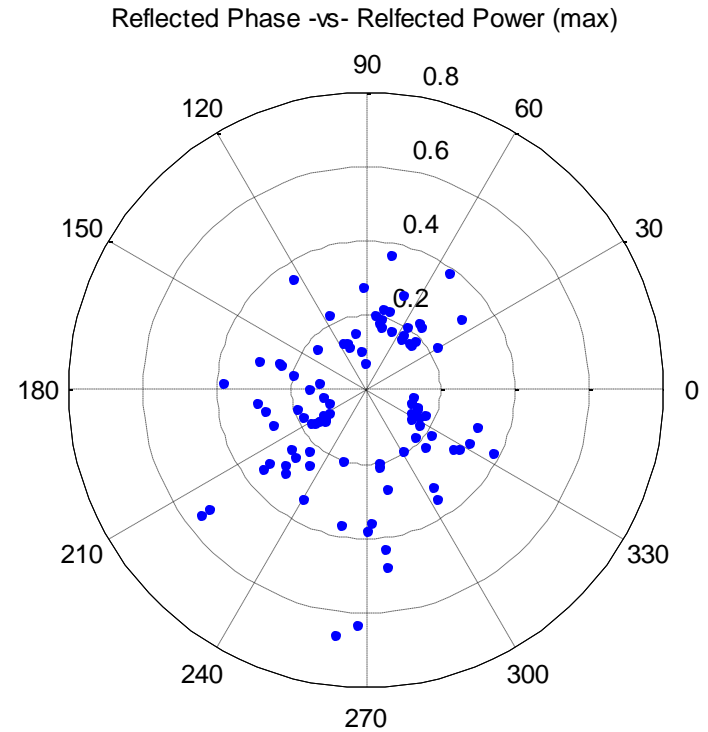
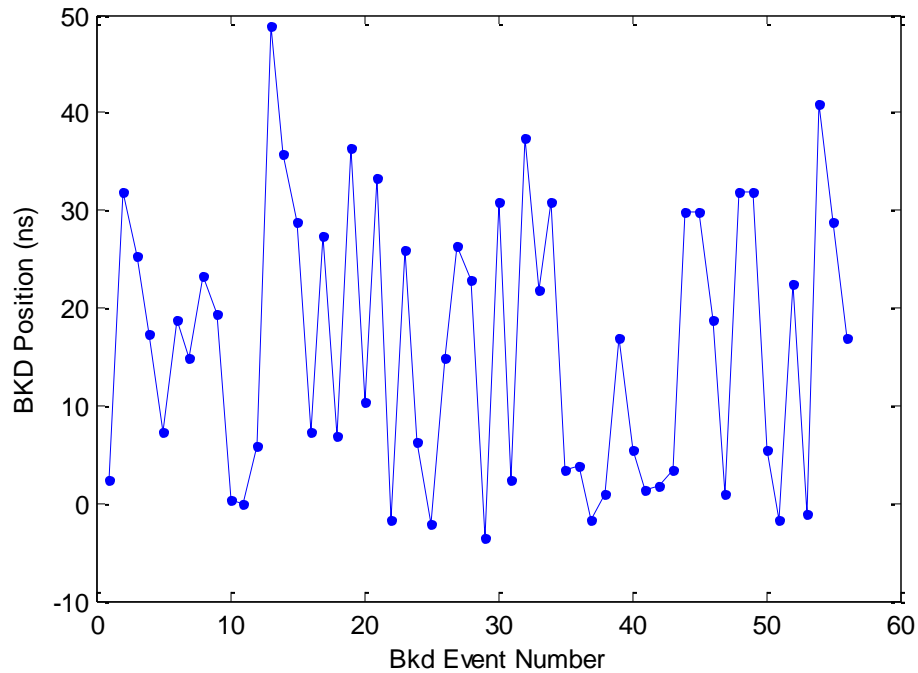
Faya Wang

Aug-24-2009

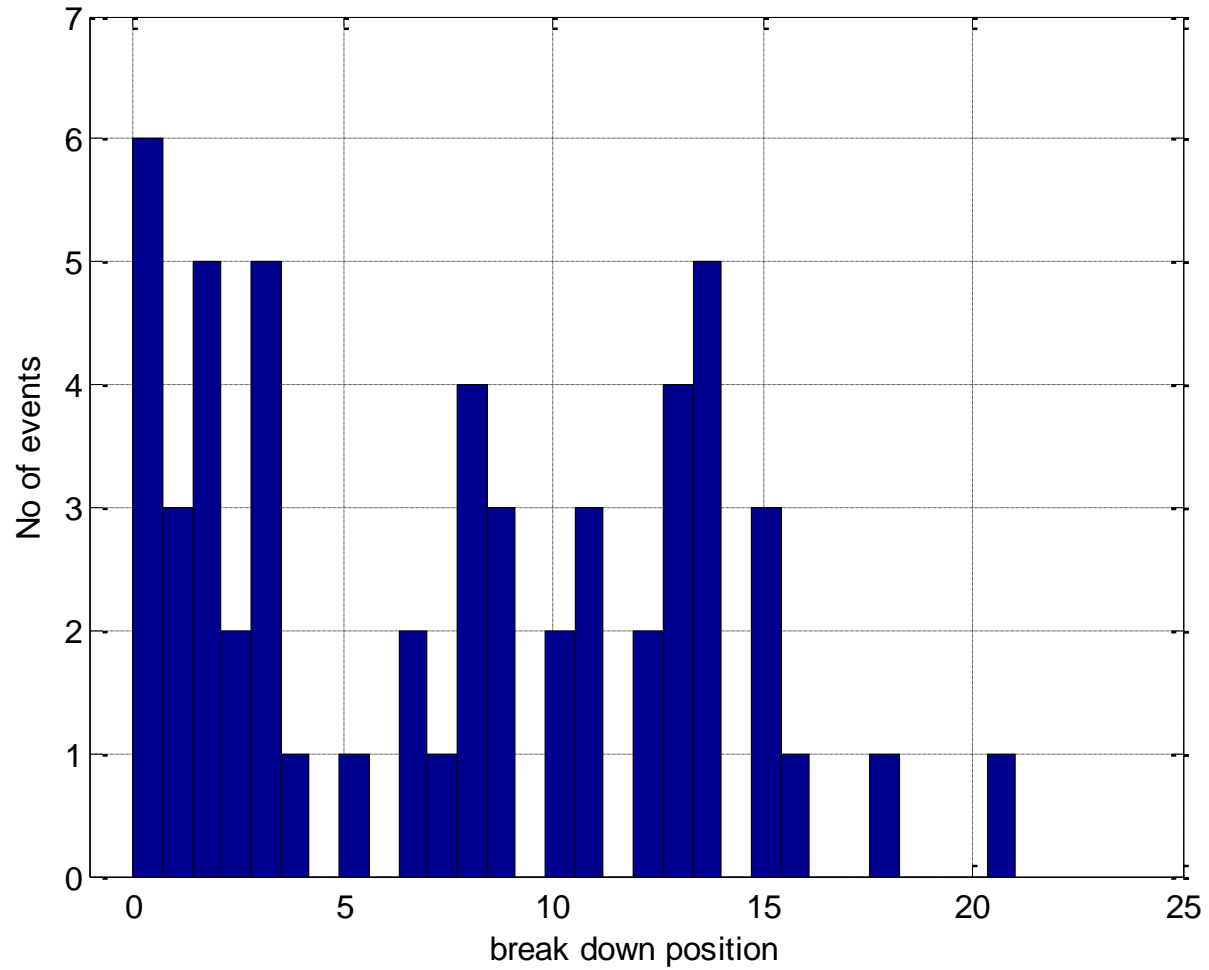
RF process history of T24. Pulse width is about 100 ns during high power process.



Breakdown analysis result



Roughly translated into breakdowns per cell



T24_CERN_Disk Vacuum History in Aug 09 During Operation

